

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination OGASAWARA ET AL.	
		Examiner Leo T. Hinze	Art Unit 2854	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0120220 A1	06-2004	Ogasawara, Kenji	368/080
	B	US-6,807,128 B2	10-2004	Yiu, Chih Hao	368/220
	C	US-5,270,993 A	12-1993	Besson et al.	368/80
	D	US-5,231,612 A	07-1993	Allgaier et al.	368/47
	E	US-5,734,474 A	03-1998	Haecker et al.	356/623
	F	US-6,731,571 B2	05-2004	Yiu, Chih Hao	368/79
	G	US-6,804,173 B2	10-2004	Yiu, Chih Hao	368/220
	H	US-2004/0125702 A1	07-2004	Kitajima et al.	368/080
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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